



# 4-Mbit (256 K × 16) Static RAM

#### **Features**

- Temperature ranges
  - □ Automotive-A: -40 °C to 85 °C
  - □ Automotive-E: -40 °C to 125 °C
- Pin and function compatible with CY7C1041BNV33
- High speed
  - $\exists t_{AA} = 10 \text{ ns (Automotive-A)}$
  - $\Box$  t<sub>AA</sub> = 12 ns (Automotive-E)
- Low active power
- □ 432 mW (max)
- 2.0 V data retention
- Automatic power down when deselected
- TTL-compatible inputs and outputs
- Easy memory expansion with CE and OE features
- Available in Pb-free and non Pb-free 44-pin 400 Mil SOJ, 44-pin TSOP II and 48-ball FBGA packages

### **Functional Description**

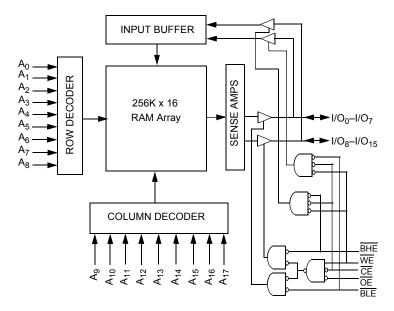
The CY7C1041CV33 Automotive is a high performance CMOS static RAM organized as 262,144 words by 16 bits.

 $\overline{\text{To}}$  write to the device, take Chip Enable  $\overline{(CE)}$  and Write Enable  $\overline{(WE)}$  inputs LOW. If Byte Low Enable  $\overline{(BLE)}$  is LOW, then data from I/O pins  $(I/O_0$  through I/O<sub>7</sub>), is written into the location specified on the address pins  $(A_0$  through  $A_{17}$ ). If Byte High Enable  $\overline{(BHE)}$  is LOW, then data from I/O pins  $\overline{(I/O_8)}$  through I/O<sub>15</sub>) is written into the location specified on the address pins  $\overline{(A_0)}$  through  $\overline{(A_1)}$ .

To read from the device, take Chip Enable ( $\overline{\text{CE}}$ ) and Output Enable ( $\overline{\text{OE}}$ ) LOW while forcing the Write Enable (WE) HIGH. If Byte Low Enable (BLE) is LOW, then data from the memory location specified by the address pins appear on I/O<sub>0</sub> to I/O<sub>7</sub>. If Byte High Enable (BHE) is LOW, then data from memory appears on I/O<sub>8</sub> to I/O<sub>15</sub>. For more information, see the Truth Table on page 10 for a complete description of Read and Write modes.

The input and output pins (I/O $_0$  through I/O $_{15}$ ) are <u>placed</u> in a high impedance state when <u>the</u> device is des<u>elected</u> (<u>CE HIGH</u>), the outputs <u>are disabled</u> (<u>OE HIGH</u>), the <u>BHE</u> and <u>BLE</u> are disa<u>bled</u> (<u>BHE</u>, <u>BLE HIGH</u>), or during a write operation (<u>CE LOW and WE LOW</u>).

### **Logic Block Diagram**



## CY7C1041CV33 Automotive



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### **Selection Guide**

Descriptio	n	-10	-12	-20	Unit
Maximum Access Time		10	12	20	ns
Maximum Operating Current	Automotive-A	100	-	85	mA
	Automotive-E	_	120	90	mA
Maximum CMOS Standby Current	Automotive-A	10	-	10	mA
	Automotive-E	_	15	15	mA

### **Pin Configuration**

Figure 1. 44-pin SOJ/TSOP II (Top View) [1]

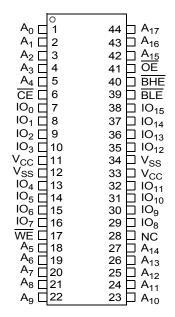
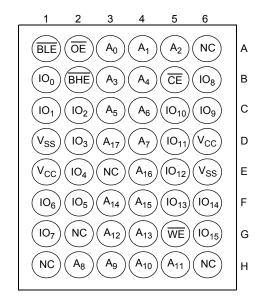


Figure 2. 48-ball FBGA Pinout (Top View) [1]



#### Note

<sup>1.</sup> NC pins are not connected on the die.



### **Pin Definitions**

Pin Name	SOJ, TSOP Pin Number	BGA Pin Number	I/O Type	Description
A <sub>0</sub> -A <sub>17</sub>	1–5, 18–27, 42–44	A3, A4, A5, B3, B4, C3, C4, D4, H2, H3, H4, H5, G3, G4, F3, F4, E4, D3	Input	Address Inputs. Used to select one of the address locations.
I/O <sub>0</sub> –I/O <sub>15</sub>	7–10,13–16, 29–32, 35–38	B1, C1, C2, D2, E2, F2, F1, G1, B6, C6, C5, D5, E5, F5, F6, G6	Input or Output	<b>Bidirectional Data I/O lines</b> . Used as input or output lines depending on operation.
NC	28	A6, E3, G2, H1, H6	No Connect	No Connects. Not connected to the die.
WE	17	G5	Input or Control	Write Enable Input, Active LOW. When selected LOW, a write is conducted. When deselected HIGH, a read is conducted.
CE	6	B5	Input or Control	Chip Enable Input, Active LOW. When LOW, selects the chip. When HIGH, deselects the chip.
BHE, BLE	40, 39	B2, A1	Input or Control	
ŌĒ	41	A2	Input or Control	<b>Output Enable, Active LOW</b> . Controls the direction of the I/O pins. When LOW, the I/O pins are allowed to behave as outputs. When deasserted HIGH, the I/O pins are tri-stated and act as input data pins.
V <sub>SS</sub>	12, 34	D1, E6	Ground	Ground for the Device. Connected to ground of the system.
V <sub>CC</sub>	11, 33	D6, E1	Power Supply	Power Supply Inputs to the Device.



### **Maximum Ratings**

Exceeding maximum ratings may impair the useful life of the device. These user guidelines are not tested.

Storage Temperature ......-65 °C to +150 °C

Ambient Temperature with

Power Applied .......55 °C to +125 °C

Supply Voltage on  $V_{CC}$  Relative to  $\mbox{GND}^{[2]}$  ..–0.5 V to +4.6 V

DC Voltage Applied to Outputs in High Z State  $^{[2]}$  ......-0.5 V to V  $_{\rm CC}$  + 0.5 V

DC Input Voltage<sup>[2]</sup> ......–0.5 V to V<sub>CC</sub> + 0.5 V

Current into Outputs (LOW)	20 mA
Static Discharge Voltage(MIL-STD-883, Method 3015)	> 2001 V
Latch Up Current	> 200 mA

### **Operating Range**

Range	Ambient Temperature (T <sub>A</sub> )	V <sub>CC</sub>		
Automotive-A	–40 °C to +85 °C	3.3 V ± 10%		
Automotive-E	–40 °C to +125 °C			

### **Electrical Characteristics**

Over the Operating Range

Doromotor	Description	Test Condition	-10		-12		-20		Unit	
Parameter	Description	rest Condition	Min	Max	Min	Max	Min	Max	Unit	
V <sub>OH</sub>	Output HIGH Voltage	$V_{CC}$ = Min, $I_{OH}$ = $-4.0$ i	mΑ	2.4	-	2.4	_	2.4	_	V
$V_{OL}$	Output LOW Voltage	V <sub>CC</sub> = Min, I <sub>OL</sub> = 8.0 m.	A	_	0.4	_	0.4	-	0.4	V
$V_{IH}$	Input HIGH Voltage			2.0	V <sub>CC</sub> + 0.3	2.0	$V_{CC} + 0.3$	2.0	V <sub>CC</sub> + 0.3	V
V <sub>IL</sub> [2]	Input LOW Voltage			-0.3	0.8	-0.3	0.8	-0.3	0.8	V
I <sub>IX</sub>	Input Leakage	$GND \le V_1 \le V_{CC}$	Auto-A	<b>–</b> 1	+1	_	_	-1	+1	μΑ
	Current		Auto-E	_	-	-20	+20	-20	+20	
I <sub>OZ</sub>	Output Leakage	$GND \le V_{OUT} \le V_{CC}$	Auto-A	-1	+1	_	_	<b>–</b> 1	+1	μΑ
	Current	Output disabled	Auto-E	_	-	-20	+20	-20	+20	
I <sub>CC</sub>	V <sub>CC</sub> Operating	V <sub>CC</sub> = Max,	Auto-A	_	100	_	_	_	85	mA
	Supply Current	$f = f_{MAX} = 1/t_{RC}$	Auto-E	_	-	_	120	_	90	
I <sub>SB1</sub>	Automatic CE	Max $V_{CC}$ , $\overline{CE} \ge V_{IH}$ ,	Auto-A	_	40	_	_	_	40	mA
	Power Down Current —TTL Inputs	$V_{IN} \ge V_{IH}$ , or $V_{IN} \le V_{IL}$ , f = f <sub>MAX</sub>	Auto-E	-	_	-	45	-	45	
I <sub>SB2</sub>	Automatic CE	Max V <sub>CC</sub> ,	Auto-A	_	10	_	_	_	10	mA
	Power Down Current — CMOS Inputs	$CE \ge V_{CC} - 0.3 \text{ V},$ $V_{IN} \ge V_{CC} - 0.3 \text{ V},$ or $V_{IN} \le 0.3 \text{ V}, f = 0$	Auto-E	_	-	_	15	-	15	

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<sup>2.</sup>  $V_{IL}$  (min) = -2.0 V and  $V_{IH}$ (max) =  $V_{CC}$  + 0.5 V for pulse durations of less than 20 ns.



### Capacitance

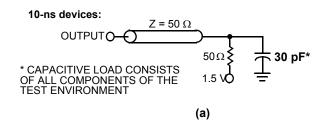
Parameter [3]	Description	Test Conditions	Max	Unit
C <sub>IN</sub>	Input Capacitance	$T_A = 25 ^{\circ}\text{C}, f = 1 \text{MHz}, V_{CC} = 3.3 \text{V}$	8	pF
C <sub>OUT</sub>	Output Capacitance		8	pF

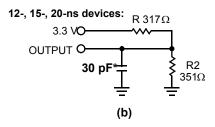
### **Thermal Resistance**

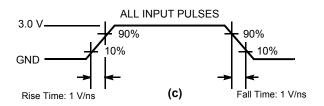
I	Parameter [3]	Description	Test Conditions	44-pin SOJ	44-pin TSOP II	48-ball FBGA	Unit
	$\Theta_{JA}$		Test conditions follow standard test methods and procedures for	25.99	42.96	38.15	°C/W
	$\Theta_{JC}$	LITERIA DESISIANCE	measuring thermal impedance, per EIA/JESD51	18.8	10.75	9.15	°C/W

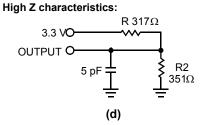
### **AC Test Loads and Waveforms**

Figure 3. AC Test Loads and Waveforms [4]









#### Notes

- Tested initially and after any design or process changes that may affect these parameters.
   AC characteristics (except High Z) for 10 ns parts are tested using the load conditions shown in Figure 3 (a). All other speeds are tested using the Thevenin load shown in Figure 3 (b). High Z characteristics are tested for all speeds using the test load shown in Figure 3 (d).



### **Switching Characteristics**

Over the Operating Range [5]

	Down to the	-10			12	-2	20	11.14	
Parameter	eter Description -		Min	Max	Min	Max	Min	Max	Unit
Read Cycle									
t <sub>power</sub> <sup>[6]</sup>	V <sub>CC</sub> (Typical) to the First Access		100	_	100	_	100	_	μS
t <sub>RC</sub>	Read Cycle Time		10	_	12	_	20	_	ns
t <sub>AA</sub>	Address to Data Valid		_	10	_	12	_	20	ns
t <sub>OHA</sub>	Data Hold from Address Change		3	_	3	_	3	_	ns
t <sub>ACE</sub>	CE LOW to Data Valid		_	10	_	12	_	20	ns
t <sub>DOE</sub>	OE LOW to Data Valid	Auto-A	_	5	_	6	_	8	ns
		Auto-E	_	-	_	7	_	8	
t <sub>LZOE</sub>	OE LOW to Low Z <sup>[7]</sup>		0	-	0	-	0	-	ns
t <sub>HZOE</sub>	OE HIGH to High Z <sup>[7, 8]</sup>		_	5	_	6	_	8	ns
t <sub>LZCE</sub>	CE LOW to Low Z <sup>[7]</sup>		3	-	3	_	3	-	ns
t <sub>HZCE</sub>	CE HIGH to High Z <sup>[7, 8]</sup>		_	5	_	6	_	8	ns
t <sub>PU</sub>	CE LOW to Power Up	0	-	0	-	0	-	ns	
t <sub>PD</sub>	CE HIGH to Power Down		_	10	_	12	_	20	ns
t <sub>DBE</sub>	Byte Enable to Data Valid	Auto-A	_	5	_	6	_	8	ns
		Auto-E	_	_	_	7	_	8	
t <sub>LZBE</sub>	Byte Enable to Low Z		0	_	0	_	0	_	ns
t <sub>HZBE</sub>	Byte Disable to High Z		_	6	_	6	_	8	ns
Write Cycle	9, 10]								
t <sub>WC</sub>	Write Cycle Time		10	_	12	_	20	_	ns
t <sub>SCE</sub>	CE LOW to Write End		7	_	8	_	10	_	ns
t <sub>AW</sub>	Address Setup to Write End		7	_	8	_	10	-	ns
t <sub>HA</sub>	Address Hold from Write End		0	_	0	_	0	-	ns
t <sub>SA</sub>	Address Setup to Write Start		0	-	0	_	0	-	ns
t <sub>PWE</sub>	WE Pulse Width		7	-	8	_	10	-	ns
t <sub>SD</sub>	Data Setup to Write End		5	-	6	_	8	-	ns
t <sub>HD</sub>	Data Hold from Write End		0	-	0	_	0	-	ns
t <sub>LZWE</sub>	WE HIGH to Low Z <sup>[7]</sup>		3	_	3	_	3	_	ns
t <sub>HZWE</sub>	WE LOW to High Z <sup>[7, 8]</sup>		_	5	_	6	_	8	ns
t <sub>BW</sub>	Byte Enable to End of Write		7	_	8	_	10	_	ns

- 5. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, and input pulse levels of 0 to 3.0 V.
- 6. t<sub>POWER</sub> gives the minimum amount of time that the power supply is at typical V<sub>CC</sub> values until the first memory access is performed.
- At any temperature and voltage condition, t<sub>HZCE</sub> is less than t<sub>LZCE</sub>, t<sub>HZBE</sub> is less than t<sub>LZCE</sub>, t<sub>HZDE</sub> is less than t<sub>L</sub>
- on the internal write time of the memory is defined by the overlap of CE LOW, WE LOW, and BHE/BLE LOW, CE, WE, and BHE/BLE must be LOW to initiate a write. The transition of these signals terminate the write. The input data setup and hold timing is referenced to the leading edge of the signal that terminates the write.

  10. The minimum Write cycle time for Write Cycle No. 3 (WE controlled, OE LOW) is the sum of t<sub>HZWE</sub> and t<sub>SD</sub>.



### **Switching Waveforms**

Figure 4. Read Cycle No. 1 (Address Transition Controlled)[11, 12]

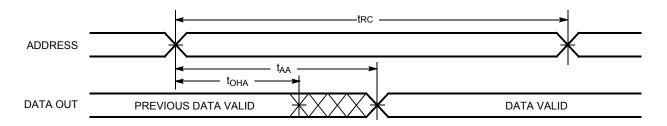
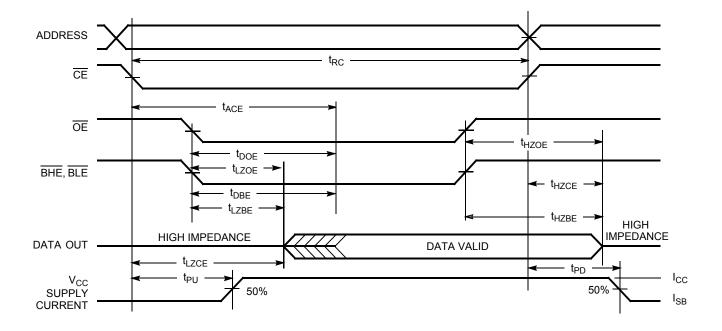


Figure 5. Read Cycle No. 2 (OE Controlled)[12, 13]



#### Notes

<sup>11.</sup> Device is continuously selected.  $\overline{OE}$ ,  $\overline{CE}$ ,  $\overline{BHE}$ , and/or  $\overline{BLE}$  = V<sub>IL</sub>. 12.  $\overline{WE}$  is HIGH for read cycle. 13. Address valid prior to or coincident with  $\overline{CE}$  transition LOW.



### Switching Waveforms (continued)

Figure 6. Write Cycle No. 1 (CE Controlled)[14, 15]

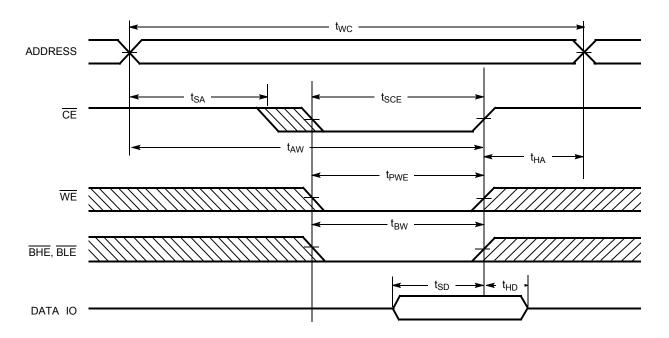
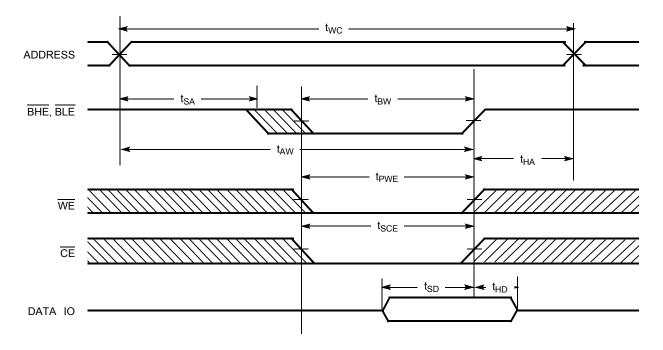


Figure 7. Write Cycle No. 2 (BLE or BHE Controlled)

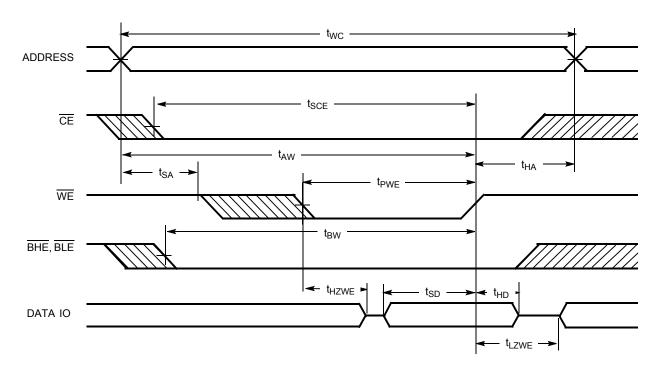


<sup>14.</sup> Data IO is high impedance if OE, BHE, and/or BLE = V<sub>IH</sub>. 15. If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high impedance state.



## Switching Waveforms (continued)

Figure 8. Write Cycle No. 3 (WE Controlled, OE LOW)



### **Truth Table**

CE	OE	WE	BLE	ВНЕ	I/O <sub>0</sub> –I/O <sub>7</sub>	I/O <sub>8</sub> -I/O <sub>15</sub>	Mode	Power
Н	X	X	X	X	High Z	High Z	Power Down	Standby (I <sub>SB</sub> )
L	L	Н	L	Ш	Data Out	Data Out	Read – All Bits	Active (I <sub>CC</sub> )
			Г	Н	Data Out	High Z	Read – Lower Bits Only	Active (I <sub>CC</sub> )
			Н	L	High Z	Data Out	Read – Upper Bits Only	Active (I <sub>CC</sub> )
L	X	L	L	L	Data In	Data In	Write – All Bits	Active (I <sub>CC</sub> )
			L	Н	Data In	High Z	Write – Lower Bits Only	Active (I <sub>CC</sub> )
			Н	L	High Z	Data In	Write – Upper Bits Only	Active (I <sub>CC</sub> )
L	Н	Н	Х	Χ	High Z	High Z	Selected, Outputs Disabled	Active (I <sub>CC</sub> )
L	Х	Х	H	Н	High Z	High Z	Selected, Outputs Disabled	Active (I <sub>CC</sub> )



### Ordering Information

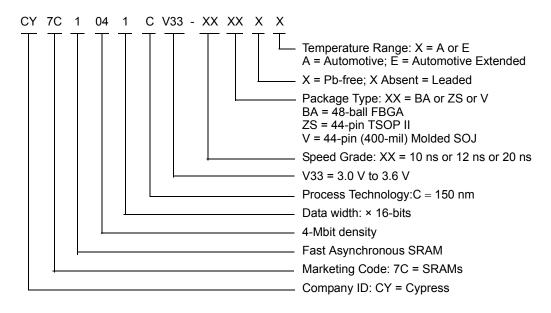
Cypress offers other versions of this type of product in many different configurations and features. The below table contains only the list of parts that are currently available. For a complete listing of all options, visit the Cypress website at <a href="https://www.cypress.com/products">www.cypress.com/products</a> or contact your local sales representative.

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Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
10	CY7C1041CV33-10BAXA	51-85106	48-ball FBGA (Pb-free)	Automotive-A
	CY7C1041CV33-10ZSXA	51-85087	44-pin TSOP II (Pb-free)	
12	CY7C1041CV33-12BAXE	51-85106	48-ball FBGA (Pb-free)	Automotive-E
	CY7C1041CV33-12ZSXE	51-85087	44-pin TSOP II (Pb-free)	
20	CY7C1041CV33-20ZSXA	51-85087	44-pin TSOP II (Pb-free)	Automotive-A
	CY7C1041CV33-20VXE		44-pin (400-mil) Molded SOJ (Pb-free)	Automotive-E
	CY7C1041CV33-20ZSXE		44-pin TSOP II (Pb-free)	

Please contact your local Cypress sales representative for availability of these parts

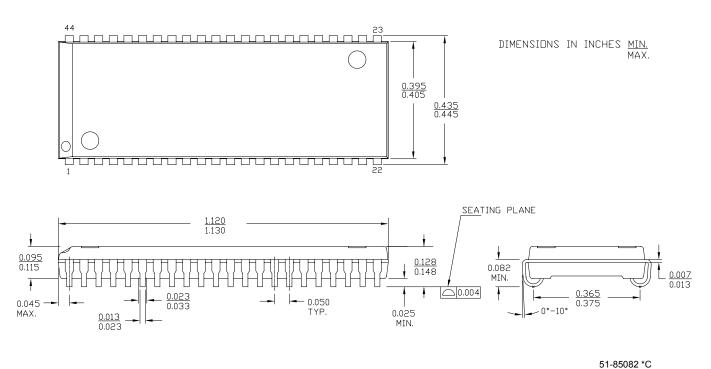
#### Ordering Code Definitions





### **Package Diagrams**

Figure 9. 44-pin SOJ 400 Mils V44.4, 51-85082

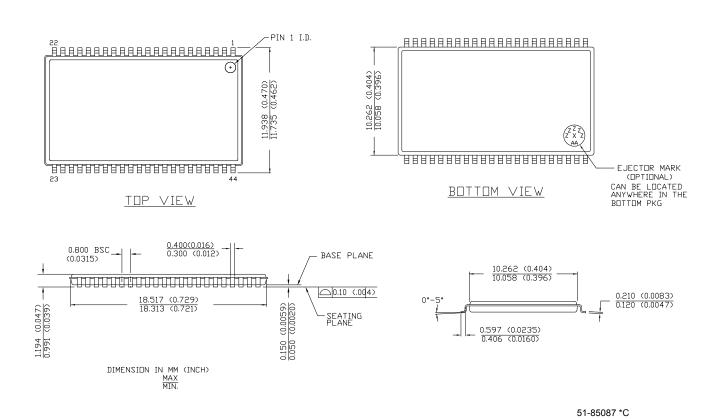


31-03002



### Package Diagrams (continued)

Figure 10. 44-pin TSOP Z44-II, 51-85087

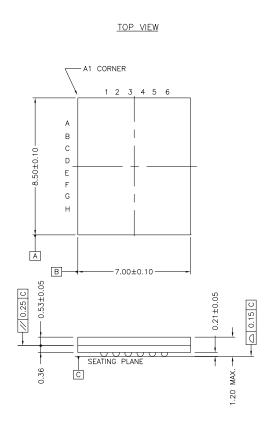


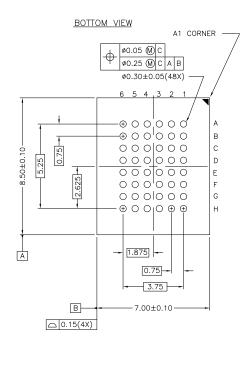
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### Package Diagrams (continued)

Figure 11. 48-ball FBGA (7.0 × 8.5 × 1.2 mm) BA48A, 51-85106





51-85106 \*F



## **Acronyms**

Acronym	Description			
CE	chip enable			
CMOS	complementary metal oxide semiconductor			
FBGA	fine-pitch ball grid array			
I/O	input/output			
OE	output enable			
SOJ	small outline J-lead			
SRAM	static random access memory			
TSOP	thin small outline package			
TTL	transistor-transistor logic			
WE	Write Enable			

### **Document Conventions**

### **Units of Measure**

Symbol	Unit of Measure		
°C	degree Celcius		
MHz	Mega Hertz		
μΑ	micro Amperes		
μs	micro seconds		
mA	milli Amperes		
mm	milli meter		
ms	milli seconds		
mW	milli Watts		
ns	nano seconds		
Ω	ohms		
%	percent		
pF	pico Farad		
V	Volts		
W	Watts		



# **Document History Page**

Document Title: CY7C1041CV33 Automotive, 4-Mbit (256 K × 16) Static RAM Document Number: 001-67307						
REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change		
**	3187164	03/03/2011	PRAS	Separation of the automotive datasheet from CY7C1041CV33 spec no. 38-05134 Rev. *K. Further rev of 38-05134 would include only industrial / commercial parts.		
*A	3265070	05/24/2011	PRAS	Updated Functional Description (Removed "For best practice recommendations, refer to the Cypress application note AN1064, SRAM System Guidelines.").		



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